Applicability of non-linear modelling methods based on vectorial large-signal measurements to MOSFETs

D. Schreurs, E. Vandamme, S. Vandenberghe, G. Carchon and B. Nauwelaers. "Applicability of non-linear modelling methods based on vectorial large-signal measurements to MOSFETs." 2000 MTT-S International Microwave Symposium Digest 00.1 (2000 Vol. I [MWSYM]): 457-460.

Non-linear MOSFET models are mostly indirectly derived from DC, C-V and S-parameter measurements. We present two accurate modelling techniques that directly determine the MOSFET state-functions from high-frequency vectorial large-signal measurements. The parameter optimisation method quickly generates models for specific applications, while the extraction method is preferred to obtain general models.

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